

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Attorney Dkt 65.0372

Kenneth R. WILSHER

Group Art Unit: 2825

Serial No.: 10/066,123

Examiner:

Filed: January 30, 2002

For: PICA System Timing Measurement & Calibration

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on May 25, 2002.

May 25, 2002

Bruce D. Riter, Reg. No. 27,379

DISCLOSURE STATEMENT UNDER 37 CFR §§1.56, 1.97 & 1.98

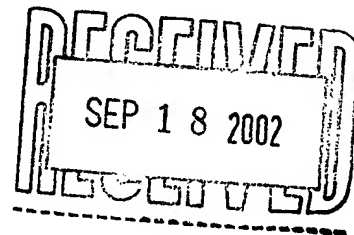
HON. COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, D.C. 20231

Sir:

Transmitted herewith are the following:

1. Copies of the following document(s):

- a. U.S. Patent No. 5,940,545 of Kash *et al.*, dated Aug. 17, 1999
- b. U.S. Patent No. 6,028,952 of Kash *et al.*, dated Feb. 22, 2000
- c. U.S. Patent No. 6,172,512 B1 of Evans *et al.*, dated Jan. 9, 2001
- d. U.S. Patent No. 6,304,668 B1 of Evans *et al.*, dated Oct. 16, 2001
- e. European Patent Application EP 0 937 989 A2 published 25.08.1999
- f. J. BUDE, *Hot-carrier luminescence in Si*, PHYS. REV. B, 45(11), 15 March 1992, pages 5848-5856



- g. S. VILLA *et al.*, *Photon emission from hot electrons in silicon*, PHYS. REV. B, 52(15), 15 October 1995-I, pages 10993-10999
 - h. J. KASH *et al.*, *Full Chip Optical Imaging of Logic State Evolution in CMOS Circuits*, IEDM 96 Late News Paper (1996) 1, pages 934-936
 - i. D. KNEBEL *et al.*, *Diagnosis and Characterization of Timing-Related Defects by Time-Dependent Light Emission*, ITC PROCEEDINGS 1998
 - j. M. BRUCE *et al.*, *Waveform Acquisition from the Backside of Silicon Using Electro-Optic Probing*, PROCEEDINGS FROM THE 25TH INTERNATIONAL SYMPOSIUM FOR TESTING AND FAILURE ANALYSIS, 14-18 November 1999, pages 19-25
 - k. T. EILES *et al.*, *Optical Probing of VLSI IC's from the Silicon Backside, Proceedings from the 25th International Symposium for Testing and Failure Analysis*, 14-18 November 1999, pages 27-33
 - l. M. MCMANUS, *Picosecond Imaging Circuit Analysis of the IBM G6 Microprocessor Cache*, PROCEEDINGS FROM THE 25TH INTERNATIONAL SYMPOSIUM FOR TESTING AND FAILURE ANALYSIS, 14-18 November 1999, pages 35-38
 - m. N. GOLDBLATT *et al.*, *Unique and Practical IC Timing Analysis Tool Utilizing Intrinsic Photon Emission*, MICROELECTRONICS RELIABILITY 41 (2001) 1507-1512
 - n. G. DAJEE *et al.*, *Practical, Non-Invasive Optical Probing for Flip-Chip Devices*, ITC Paper 15.3 (Baltimore, October 28 - November 2, 2001) 433-442
 - o. IDS® PICA, *Advanced Optical Imaging for Analysis of 0.13-micron and SOI Devices*, Schlumberger Semiconductor Solutions brochure printed 3/01, four pages
2. A listing of the above-identified document(s) on a separate sheet entitled Information Disclosure Citation, as a substitute for form PTO-1449.

This Disclosure Statement is believed to be submitted before the mailing date of a first Office action on the merits. Pursuant to 37 CFR §1.97(b), Applicants respectfully request that the enclosed document be considered.


Applicants further request that the enclosed documents listed above be made of record for printing on any patent which may issue from this application, that the enclosed substitute for Form PTO-1449 be initialed to indicate that the documents have been considered, and that a copy of the initialed substitute for Form PTO-1449 be returned to the undersigned.

If this Disclosure Statement is not submitted prior to the mailing date of a first Office action on the merits, Applicants respectfully request that the enclosed document be considered under 37 CFR §1.97(c).

The Commissioner is hereby authorized to charge fees under 37 CFR §1.17 that may be required, or credit any overpayment, to deposit Account No. 19-0603 maintained in the name of Schlumberger Technologies, Inc. A duplicate of this paper is enclosed.

May 25, 2002

Respectfully Submitted,



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